

Notice of References Cited	Application/Control No. 09/702,067	Applicant(s)/Patent Under Reexamination VANDERWAL, RICHARD A.	
	Examiner Leigh McKane	Art Unit 1744	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,139,793-A	10-2000	VANDERWAL	422/1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	J	US-			
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	L	US-			
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FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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